Supporting Information

## Interface Trap-Induced Temperature Dependent Hysteresis and Mobility in $\beta$ -Ga<sub>2</sub>O<sub>3</sub> Field-Effect Transistors

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**Figure S1.** Output curves of  $I_{DS}$  – low  $V_{DS}$  at room temperature for  $V_{GS}$  = -15, -10, -5, 0, 5, and 10 V. The good linearity of output curves indicate the Ohmic contact of the  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> FET.



**Figure S2.** Transfer curve for  $V_{DS} = 1$  V in a linear scale at 180 K. The red dash line is tangential line at the maximum slope on transfer curve. The threshold voltage is defined as *x*-intercept of the red dash line.

Table S1. The density of the trapped and de-trapped charges and the time constants.

	$V_{\rm G} = 0 \ { m V}$					$V_{\rm G}$ = 10 V				
T [K]	Q1+Q2 [10 <sup>9</sup> cm <sup>-2</sup> ]	Q1 [10 <sup>9</sup> cm <sup>-</sup> 2]	τ <sub>it1</sub> [s]	Q2 [10 <sup>9</sup> cm <sup>-</sup> 2]	τ <sub>it2</sub> [s]	$Q_1+Q_2$ [10 <sup>9</sup> cm <sup>-</sup> <sup>2</sup> ]	Q1 [10 <sup>9</sup> cm <sup>-</sup> <sup>2</sup> ]	τ <sub>it1</sub> [s]	Q2 [10 <sup>9</sup> cm <sup>-</sup> 2]	τ <sub>it2</sub> [s]
280	19.23	2.33	19.41	16.9	153.13	-5.53	-2.52	3.35	-3.01	51.04
290	33.18	4.14	13.44	29.04	148.44	-7.73	-3.55	2.95	-4.18	50.72
300	38.61	4.77	6.16	33.84	72.24	-11.06	-6.09	1.73	-4.97	34
310	42.56	6.63	3.51	35.93	34.86	-10.71	-6.55	1.57	-4.16	25.35
320	42.7	5.84	1.52	36.86	13.89	-9.61	-5.69	0.95	-3.92	10.96

I - I +	$\mu WV_{DS}(Q_1 e^{-t/\tau_{it1}})$	$+ Q_2 e^{-t/\tau_{it2}}$
$I = I_0 \perp$	L	